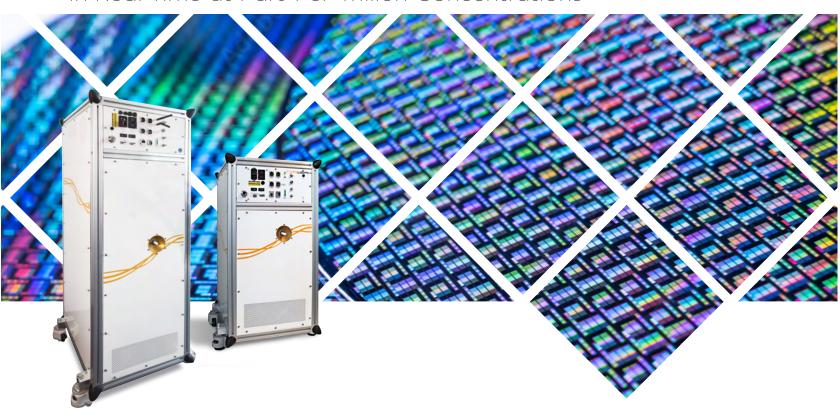


AMC Solutions

Comprehensively Measure Gas-Phase Contaminants in Real Time at Part-Per-Trillion Concentrations



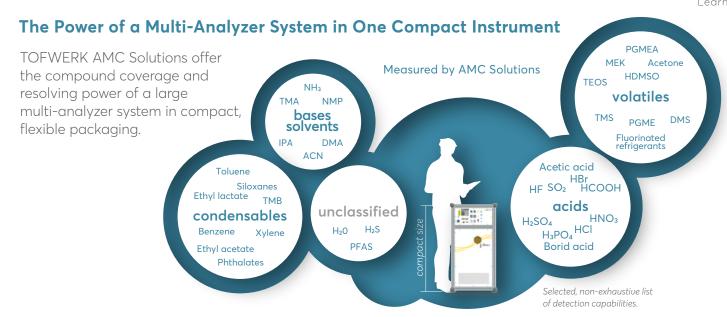
TOFWERK AMC Solutions provide fast, sensitive detection of airborne molecular contaminants (AMCs) through cutting-edge chemical ionization mass spectrometry.

Offering market-leading sensitivity and simplified mass spectra, TOFWERK AMC Solutions are ideal for semiconductor applications. They feature comprehensive compound coverage, fast, real-time sampling with up to six positive and negative reagent ions, pptV detection limits, and high-resolution compound identification. Additional features include rapid polarity switching, ultra-soft ionization, a compact design for versatile deployment, and a multi-port valve option.

TOFWERK AMC Solutions: the power of multiple analyzers for unprecedented flexibility in one compact, robust instrument.

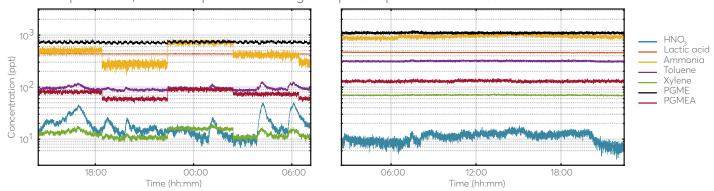






Sample Timeseries

The two panels below show highly sensitive, real-time, and simple separation of a broad range of AMCs by the AMC Monitor in a semiconductor fab environment. The panel on the left shows the measurement of transients from fab processes, while the panel on the right depicts a period of more stable ambient conditions.



Systems Specifications

Model*

Reagent Ion Switching

Concentration Range

Resolution | Sensitivity

Dimension | Weight | Power

AMC Monitor	AMC Analyzer				
Typical configuration: 4 reagent ions in 2 seconds					
ppqv - 500 ppbv					
>1000 M/ΔM 1-50 pptv	>4500 0.1-10 pptv				
480 x 615 x 850 mm 140 kg <1100 W (600 W typical)	480 x 615 x 1335 mm 170 kg <1100 W (600 W typical)				

*All instruments are CE certified.

Limit of Detection in pptv (LOD)*

Xylene	TMB	НСООН	NH3	PGME	PGMEA	HNO3	TEOS
6	5	6	50	5	7	10	5

^{*}Representative LODs evaluated using 3 standard deviations with an integration time of 1 minute for selected compounds.

